

## **AMENDMENTS TO THE SPECIFICATION**

Please replace Paragraph [0021] with the following paragraph rewritten in amendment format:

[0021] Figs. 4(1), 4(2) shows a principle of imaging by the apparatus of the preset embodiment and an example of a photographed image of light passing through a through hole.

Please replace Paragraph [0022] with the following paragraph rewritten in amendment format:

[0022] Figs. 5(1), 5(2) shows a principle of an ordinary imaging and an example of a photographed image of light passing through a through hole.

Please replace Paragraph [0025] with the following paragraph rewritten in amendment format:

[0025] Figs. 8(1), 8(2) shows a flow chart of an examination of the number of light receiving regions and an example of measured images.

Please replace Paragraph [0030] with the following paragraph rewritten in amendment format:

[0030] Figs. 13(1), 13(2) shows graphs of relations between through hole locations and through hole area values in examined results in a forward direction and a reverse direction.

Please amend the Abstract section of the specification as rewritten in amendment format.

~~Provided herein are a~~A method and an apparatus for examining foreign matters in through holes, ~~which can quickly make determinations with low costs and high accuracy. An apparatus is equipped with~~includes a light source 12 ~~provided on one side and a line sensor camera 14 (or an area sensor) provided on the other side, whereby the light source and sensor camera cooperate to inspect with~~ a work piece 10 having a plurality of through holes ~~being placed between them.~~ A parallel displacement system ~~(XY table 16)~~ is provided to translate the work piece and the line sensor camera relative to each other to allow the line sensor camera to detect light passing through the plurality of through holes in one lot, ~~and a~~An image processing device 24 ~~is provided to receive detected signals provided by the line sensor camera to obtain a plurality of binary image data corresponding to the plurality of through holes in the work piece. The image processing device is equipped with a~~and determination device that ~~makes determination as~~are also provided to determine whether foreign matters are present or absent in the through holes based on deviations among receiving light regions corresponding to the respective through holes.